

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
M122-1246SERIAL NO.  
09/517,127LIST OF ART CITED BY APPLICANT  
(Use several sheets if necessary)APPLICANT  
Scott E. Moore et al.FILING DATE  
March 12, 2000GROUP  
Unknown

## U.S. PATENT DOCUMENTS

Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
JK	AA 5,755,614	05/26/98	Adams et al.			
JK	AB 5,664,990	09/09/97	Adams et al.			
	AC					
	AD					
	AE					

## FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AF						
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	AH						

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

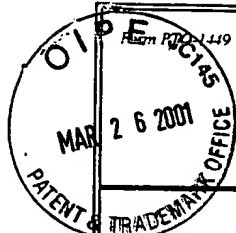
JK	AI	<a href="http://www.intratechnology.com/html/sensors.htm">http://www.intratechnology.com/html/sensors.htm</a> , Intra Technology, <i>Sensors</i> , 03/25/99, 2 pages
	AJ	<a href="http://www.ftsiinc.com/complete/analite/analite.htm">http://www.ftsiinc.com/complete/analite/analite.htm</a> , FTS, <i>Analite-SDI Turbidity Sensor</i> , 03/25/99, 1 page
	AK	<a href="http://www.customsensors.com/optimax.htm">http://www.customsensors.com/optimax.htm</a> , Custom Sensors & Technology, <i>OptiMax 6000 Series Process Photometric Analyzers</i> , 03/25/99, 2 pages
	AL	<a href="http://www.reflectronics.com/reflectronics_inc_contents.htm">http://www.reflectronics.com/reflectronics_inc_contents.htm</a> , Reflectronics, Inc., <i>Fiber Optic Backscatter Sensor</i> , 03/25/99, 1 page
	AM	<a href="http://www.honeywell.com/sensing/prodinfo/turbidity/technical/turbidity.st">http://www.honeywell.com/sensing/prodinfo/turbidity/technical/turbidity.st</a> , Gary O'Brien, Honeywell, <i>Turbidity Sensor for Electromechanical Dishwasher Control</i> , 1998-1999, 11 pages
JK	AT	<a href="http://www.imponag.com/O_automa/10970064.htm">http://www.imponag.com/O_automa/10970064.htm</a> , ABB Instrumentation, <i>The Stockroom, Photodiode Sensor</i> , 1999, 1 page

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TC 3700 MAIL ROOM

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TK	AI		<i>"The Science and Engineering of Microelectronic Fabrication"; Campbell, Stephen A.; Oxford University Press; 1996; pp. 253-257.</i>
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JS	AA	5,755,614	05/26/98	Adams et al.			
TR	AB	5,664,990	09/09/97	Adams et al.			
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TR	AI		<a href="http://www.intratechnology.com/html/sensors.htm">http://www.intratechnology.com/html/sensors.htm</a> , Intra Technology, <i>Sensors</i> , 03/25/99, 2 pages
	AJ		<a href="http://www.fisinc.com/complete/analite/analite.htm">http://www.fisinc.com/complete/analite/analite.htm</a> , FTS, <i>Analite-SDI Turbidity Sensor</i> , 03/25/99, 1 page
	AK		<a href="http://www.customsensors.com/optimax.htm">http://www.customsensors.com/optimax.htm</a> , Custom Sensors & Technology, <i>OptiMax 6000 Series Process Photometric Analyzers</i> , 03/25/99, 2 pages
	AL		<a href="http://www.reflectronics.com/reflectronics_inc_contents.htm">http://www.reflectronics.com/reflectronics_inc_contents.htm</a> , Reflectronics, Inc., <i>Fiber Optic Backscatter Sensor</i> , 03/25/99, 1 page
	AM		<a href="http://www.honeywell.com/sensing/prodinfo/turbidity/technical/turbidity.st">http://www.honeywell.com/sensing/prodinfo/turbidity/technical/turbidity.st</a> , Gary O'Brien, Honeywell, <i>Turbidity Sensor for Electromechanical Dishwasher Control</i> , 1998-1999, 11 pages
TR	AT		<a href="http://www.impomag.com/O_automa/1097O064.htm">http://www.impomag.com/O_automa/1097O064.htm</a> , ABB Instrumentation, <i>The Stockroom, Photodiode Sensor</i> , 1999, 1 page

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*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
TR	AA	5,836,805	11/17/98	Obeng			
	AB	6,066,030	5/23/00	Uzoh			
	AC	6,077,147	6/20/00	Yang et al.			
	AD	6,048,256	4/11/00	Obeng et al.			
TR	AE	5,653,624	8/5/97	Ishikawa et al.			
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	AI						

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